

Most Frequently Occurring Classifications of Patents Returned
From A Search of 10790301 on July 19, 2005

Original Classifications

3 600/407
2 73/579
2 348/163
2 356/497
2 359/9
2 600/442
2 702/14



Cross-Reference Classifications

3 324/76.19
3 356/432
3 600/476
2 73/599
2 73/602
2 73/61.49
2 73/61.79
2 324/307
2 324/457
2 356/511
2 359/29
2 359/32
2 378/17
2 378/901
2 455/306
2 600/442
2 702/76

Combined Classifications

4 600/407
4 600/442
3 73/599
3 324/76.19
3 356/432
3 600/476
2 73/579
2 73/602
2 73/61.49
2 73/61.79
2 250/363.04
2 324/307
2 324/457
2 348/163
2 356/497
2 356/511
2 359/29
2 359/32
2 359/9
2 378/17
2 378/4
2 378/901
2 455/306
2 600/425
2 702/14
2 702/76

10790301_CLSTITLES1.txt
Titles of Most Frequently Occurring Classifications of Patents Returned
From A Search of 10790301 on July 19, 2005

4 600/407 (3 OR, 1 XR)
Class 600 : SURGERY
600/300 DIAGNOSTIC TESTING
600/407 .Detecting nuclear, electromagnetic, or
ultrasonic radiation

4 600/442 (2 OR, 2 XR)
Class 600 : SURGERY
600/300 DIAGNOSTIC TESTING
600/407 .Detecting nuclear, electromagnetic, or
ultrasonic radiation
600/437 ..Ultrasonic
600/442 ...Tissue attenuation or impedance measurement
or compensation

3 73/599 (1 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/570 VIBRATION
73/584 .By mechanical waves
73/596 ..Beamed
73/599 ...Attenuation measurement

3 324/76.19 (0 OR, 3 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/76.11 MEASURING, TESTING, OR SENSING ELECTRICITY, PER
SE
324/76.12 .Analysis of complex waves
324/76.19 ..Frequency spectrum analyzer

3 356/432 (0 OR, 3 XR)
Class 356 : OPTICS: MEASURING AND TESTING
356/432 FOR LIGHT TRANSMISSION OR ABSORPTION

3 600/476 (0 OR, 3 XR)
Class 600 : SURGERY
600/300 DIAGNOSTIC TESTING
600/407 .Detecting nuclear, electromagnetic, or
ultrasonic radiation
600/476 ..Visible light radiation

2 73/579 (2 OR, 0 XR)
Class 073 : MEASURING AND TESTING
73/570 VIBRATION
73/579 .Resonance, frequency, or amplitude study

2 73/602 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/570 VIBRATION
73/584 .By mechanical waves
73/596 ..Beamed
73/602 ...With signal analyzing or mathematical
processing

2 73/61.49 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/53.01 LIQUID ANALYSIS OR ANALYSIS OF THE SUSPENSION
OF SOLIDS IN A LIQUID
73/61.41 .Content or effect of a constituent of a liquid
mixture

10790301_CLSTITLES1.txt

73/61.43 ..Liquid constituent of a liquid mixture
73/61.49 ...By vibration

2 73/61.79 (0 OR, 2 XR)
Class 073 : MEASURING AND TESTING
73/53.01 LIQUID ANALYSIS OR ANALYSIS OF THE SUSPENSION
OF SOLIDS IN A LIQUID
73/61.41 .Content or effect of a constituent of a liquid
mixture
73/61.79 ..By vibration

2 250/363.04 (1 OR, 1 XR)
Class 250 : RADIANT ENERGY
250/336.1 INVISIBLE RADIANT ENERGY RESPONSIVE ELECTRIC
SIGNALLING
250/361R .with or including a luminophor
250/363.01 ..With radiant energy source
250/363.02 ...Body scanner or camera
250/363.04Emission tomography

2 324/307 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/300 PARTICLE PRECESSION RESONANCE
324/307 .Using a nuclear resonance spectrometer system

2 324/457 (0 OR, 2 XR)
Class 324 : ELECTRICITY: MEASURING AND TESTING
324/457 ELECTROSTATIC FIELD

2 348/163 (2 OR, 0 XR)
Class 348 : TELEVISION
348/162 RESPONSIVE TO NONVISIBLE ENERGY
348/163 .Sonic or ultrasonic

2 356/497 (2 OR, 0 XR)
Class 356 : OPTICS: MEASURING AND TESTING
356/450 BY LIGHT INTERFERENCE (E.G., INTERFEROMETER)
356/496 .For dimensional measurement
356/497 ..Having short coherence length source

2 356/511 (0 OR, 2 XR)
Class 356 : OPTICS: MEASURING AND TESTING
356/450 BY LIGHT INTERFERENCE (E.G., INTERFEROMETER)
356/496 .For dimensional measurement
356/511 ..Contour or profile

2 359/29 (0 OR, 2 XR)
Class 359 : OPTICS: SYSTEMS
359/1 HOLOGRAPHIC SYSTEM OR ELEMENT
359/29 .Fourier transform holography

2 359/32 (0 OR, 2 XR)
Class 359 : OPTICS: SYSTEMS
359/1 HOLOGRAPHIC SYSTEM OR ELEMENT
359/32 .For reconstructing image

2 359/9 (2 OR, 0 XR)
Class 359 : OPTICS: SYSTEMS
359/1 HOLOGRAPHIC SYSTEM OR ELEMENT
359/9 .For synthetically generating a hologram

2 378/17 (0 OR, 2 XR)

10790301_CLSTITLES1.txt

Class 378 : X-RAY OR GAMMA RAY SYSTEMS OR DEVICES
378/1 SPECIFIC APPLICATION
378/4 .Computerized tomography
378/17 ..Tilttable or nonvertical examination plane

2 378/4 (1 OR, 1 XR)
Class 378 : X-RAY OR GAMMA RAY SYSTEMS OR DEVICES
378/1 SPECIFIC APPLICATION
378/4 .Computerized tomography

2 378/901 (0 OR, 2 XR)
Class 378 : X-RAY OR GAMMA RAY SYSTEMS OR DEVICES
378/901 COMPUTER TOMOGRAPHY PROGRAM OR PROCESSOR

2 455/306 (0 OR, 2 XR)
Class 455 : TELECOMMUNICATIONS
455/130 RECEIVER OR ANALOG MODULATED SIGNAL FREQUENCY
CONVERTER
455/296 .Noise or interference elimination
455/303 ..Using plural separate signal paths
455/305 ...With balancing or neutralizing
455/306Filter in at least one path

2 600/425 (1 OR, 1 XR)
Class 600 : SURGERY
600/300 DIAGNOSTIC TESTING
600/407 .Detecting nuclear, electromagnetic, or
ultrasonic radiation
600/425 ..With tomographic imaging obtained from
electromagnetic wave

2 702/14 (2 OR, 0 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/2 .Earth science
702/14 ..Seismology

2 702/76 (0 OR, 2 XR)
Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
TESTING
702/1 MEASUREMENT SYSTEM IN A SPECIFIC ENVIRONMENT
702/57 .Electrical signal parameter measurement system
702/66 ..Waveform analysis
702/75 ...Frequency
702/76Frequency spectrum

10790301_QUAL1.txt

6298110 48
5995904 43
6075836 43
5406478 41
5343149 39
6549801 38
6374189 38
4797923 37
5499095 37
5293871 37
5602751 37
4931695 36
5739432 36
5767407 36
5902240 36
5530367 36
5331604 36
4441368 36
4546772 36
5953124 36
6028670 36
6262818 35
5426521 35
6367968 35
5817922 35
6524248 35
5867806 35
5615676 34
6353311 34
5376795 34
5309100 34
6109098 34
5237844 34
5963364 34
4561019 34
RE35148 34
6112155 34
5747810 34
5762607 34
5787888 34
5832922 34
6444192 34
6317700 34
5532976 34
5629706 33
5963929 33
5828216 32
4623855 32
4950042 32
5930384 32

PLUS Search Results for S/N 10790301, Searched July 19, 2005

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

6298110
5995904
6075836
5406478
5343149
6549801
6374189
4797923
5499095
5293871
5602751
4931695
5739432
5767407
5902240
5530367
5331604
4441368
4546772
5953124
6028670
6262818
5426521
6367968
5817922
6524248
5867806
5615676
6353311
5376795
5309100
6109098
5237844
5963364
4561019
RE35148
6112155
5747810
5762607
5787888
5832922
6444192
6317700
5532976
5629706
5963929
5828216
4623855
4950042
5930384